


<b>Search Notes</b>  	<b>Application/Control No.</b>  10590850	<b>Applicant(s)/Patent Under Reexamination</b>  FUJISAWA ET AL.
	<b>Examiner</b>  Yevgeny Valenrod	<b>Art Unit</b>  1621

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
STIC Search reviewed	11/6/2009	YV
East Search including 560/205	11/6/2009	YV
Inventor Search	11/6/2009	YV
Pat Conference with Examiners Sullivan and Zucker		

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
SEE EAST		11/6/2009	YV

/YEVEGENY VALENROD/ Examiner.Art Unit 1621	
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